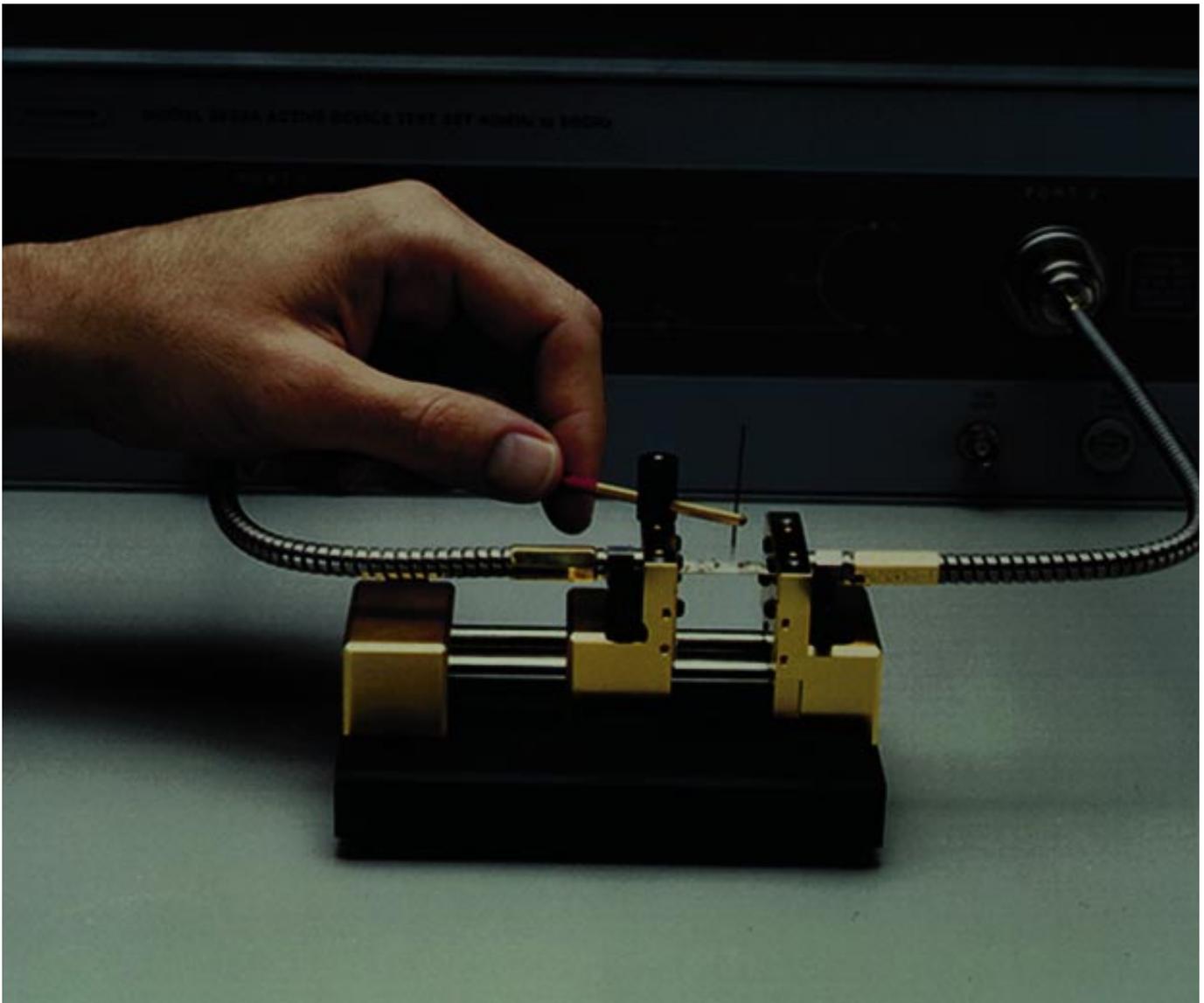


3680 Series

Universal Test Fixtures

DC to 60 GHz



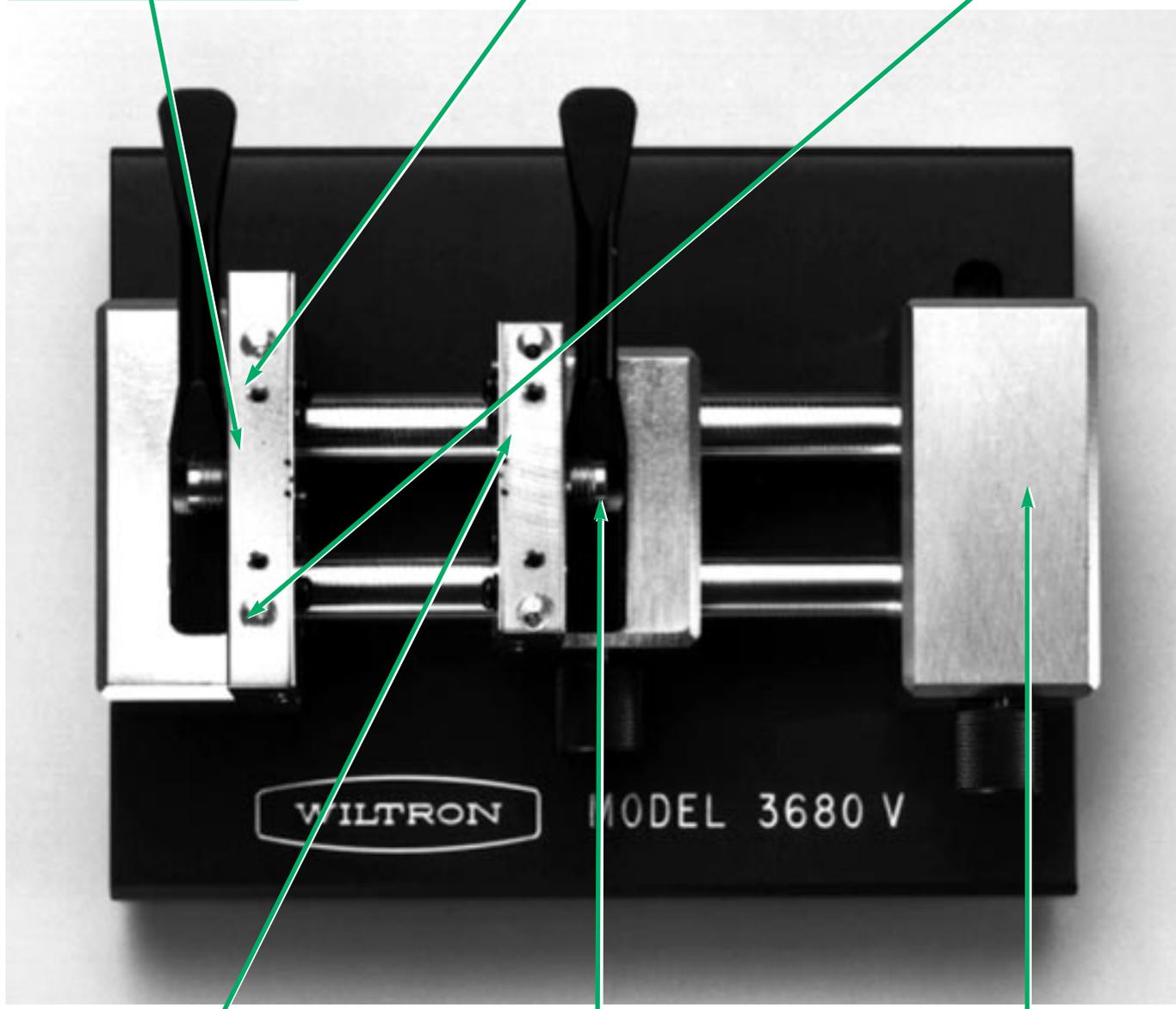
A Complete Measurement Solution

3680-20 DC to 20 GHz 3680K DC to 40 GHz 3680V DC to 60 GHz

Dielectric spacers reduce fringing capacitance for more accurate and repeatable measurements.

Solid ground contacts top and bottom allow microstrip or coplanar waveguide measurements in one fixture.

Spring-loaded jaws provide 0.1 dB repeatability on devices from 5 to 75 mil substrate thickness—no fixture modification required.



Adjustable launch measures substrates up to 2" long without requiring custom center sections.

K Connector® yields DC to 40 GHz, V Connector® yields DC to 60 GHz operation for device measurement over any coaxial frequency range.

Line offset up to $\pm\frac{1}{2}$ inch eliminates the need for custom fixtures.

Complete Measurement Solution

Substrate Measurement Capability

Providing substrate measurement capability for your microstrip or coplanar waveguide designs, the 3680 Series Universal Test Fixtures allow accurate, repeatable transitions from coax to microstrip or coax to coplanar waveguide (CPW). Complete substrate measurement systems comprised of a Universal Test Fixture, a vector or scalar network analyzer, and a "substrate" Calibration Kit can fulfill your microstrip or CPW test needs.

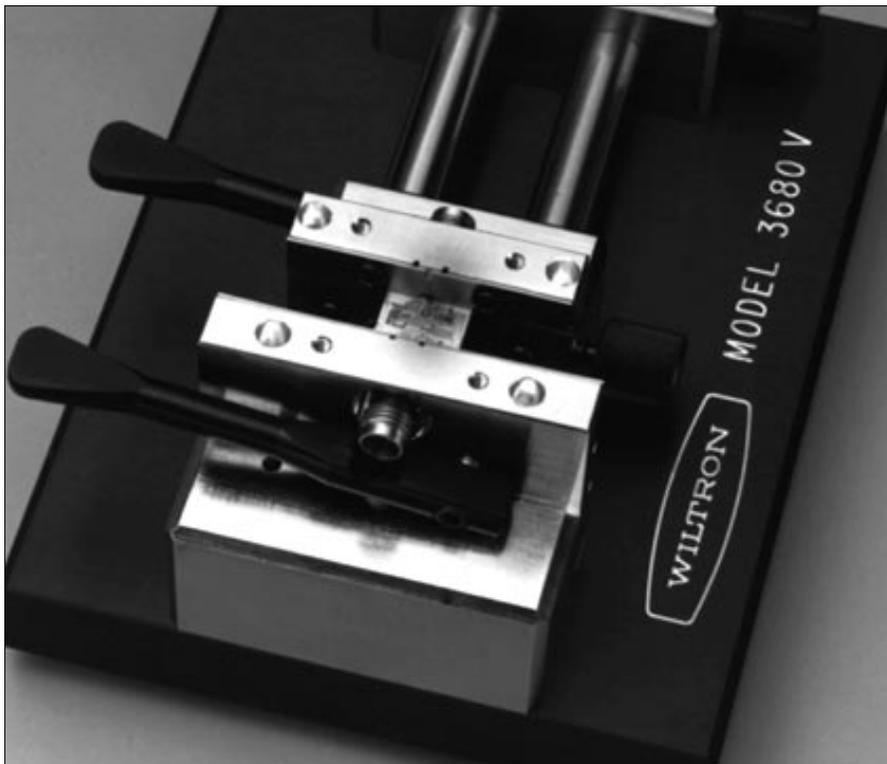
Anritsu Wiltron provides the complete measurement solution, the test fixtures, the calibration kits, and the test equipment for measurements on substrate devices. Our total system responsibility ensures compatible system components, designed to work together properly. Guaranteed system specs provide assurance that your test results are accurate and verifiable.

Universal Test Fixtures

The most critical part of any substrate measurement system is the launching fixture. It must be simple yet flexible, easy to use, and most of all provide accurate, repeatable measurements. Our Universal Test Fixtures are designed to meet these

requirements. Three versions of the Universal Test Fixture are available: the 3680-20, DC to 20 GHz; the 3680K, DC to

40 GHz; and the 3680V, DC to 60 GHz. The fixture consists of a fixed connector and a movable connector that can be positioned for substrates up to 2 inches long. No center section is required. The substrate is held in place between spring-loaded jaws. This allows the fixture to accommodate different devices without requiring a custom center section for each different length. The unique jaw action ensures solid, repeatable electrical contact. The jaw tension is defined by the force of a spring, independent of human judgement errors. This means the tension will always be the same, providing more repeatable measurements. Dielectric rods behind the jaws accurately position the substrate away from the launch to reduce fringing capacitance and contribute to the fixture's excellent repeatability. With a Universal Test Fixture you can be sure your measurements are both accurate and repeatable.



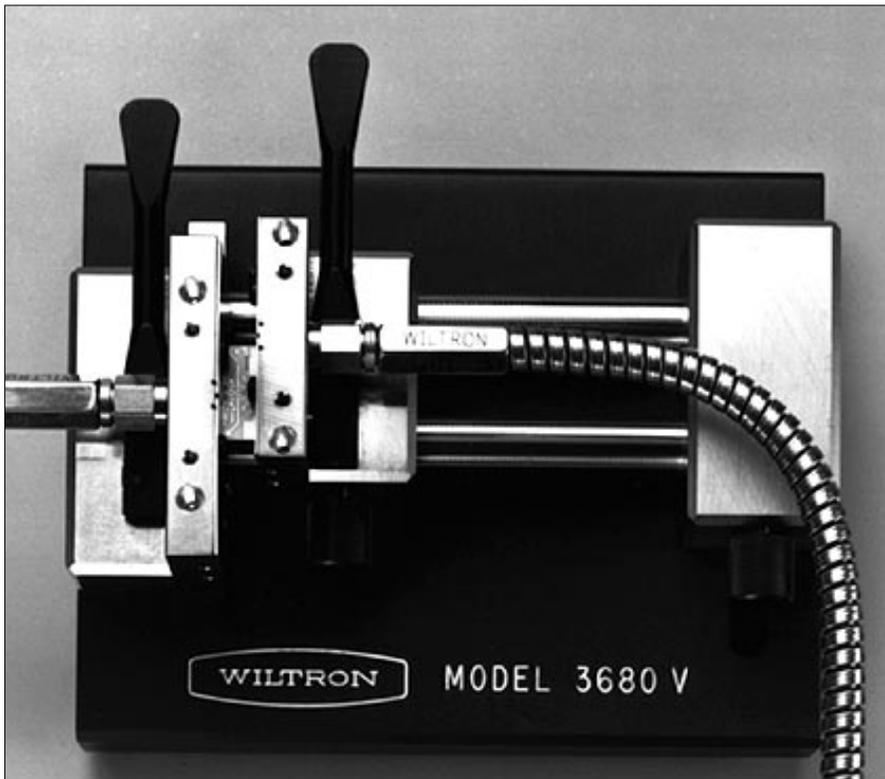
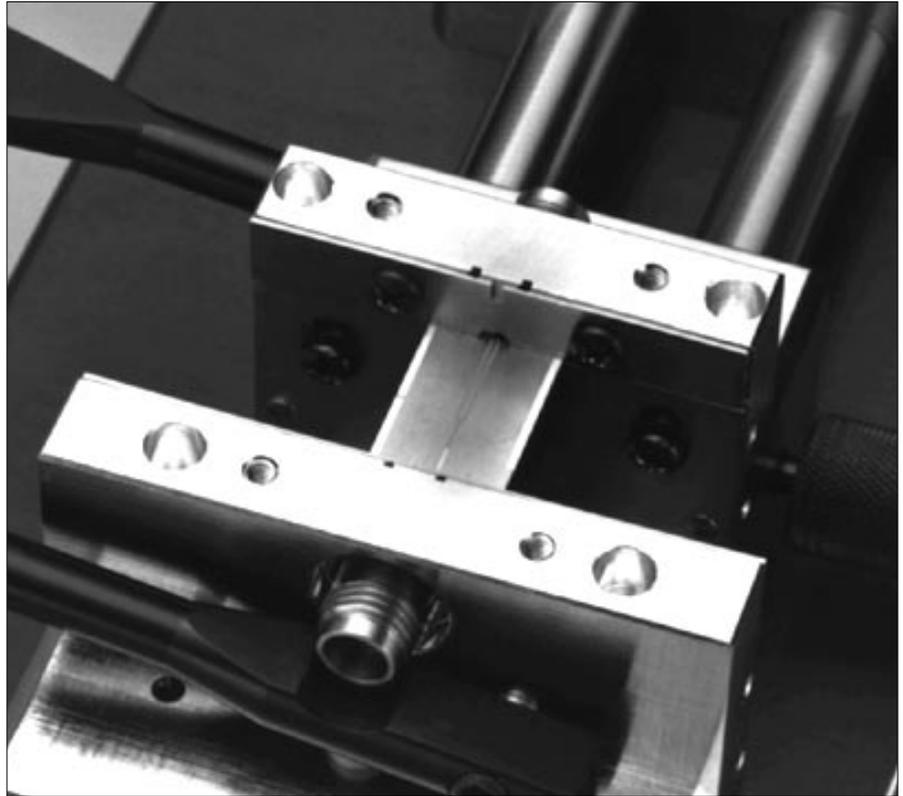
Microwave circuit provided by Avantek, Inc.

Design for Performance without Compromise

Microstrip or Coplanar Waveguide Measurements

The unique design of the 3680 provides measurement capability for either microstrip or coplanar waveguide (CPW) designs. All that is required is a simple jaw change. The 3680 does the job of two fixtures, saving you time and money.

A substrate measurement system with the 360B or 37200A VNA is the only measurement system capable of directly providing microstrip dispersion compensation. Microstrip is a dispersive media – phase shift is not linear with respect to frequency. Our Vector Network Analyzer's ability to compensate for this dispersion can dramatically improve vector measurement accuracy and provide you with the most accurate vector measurements possible.



Offset Measurements

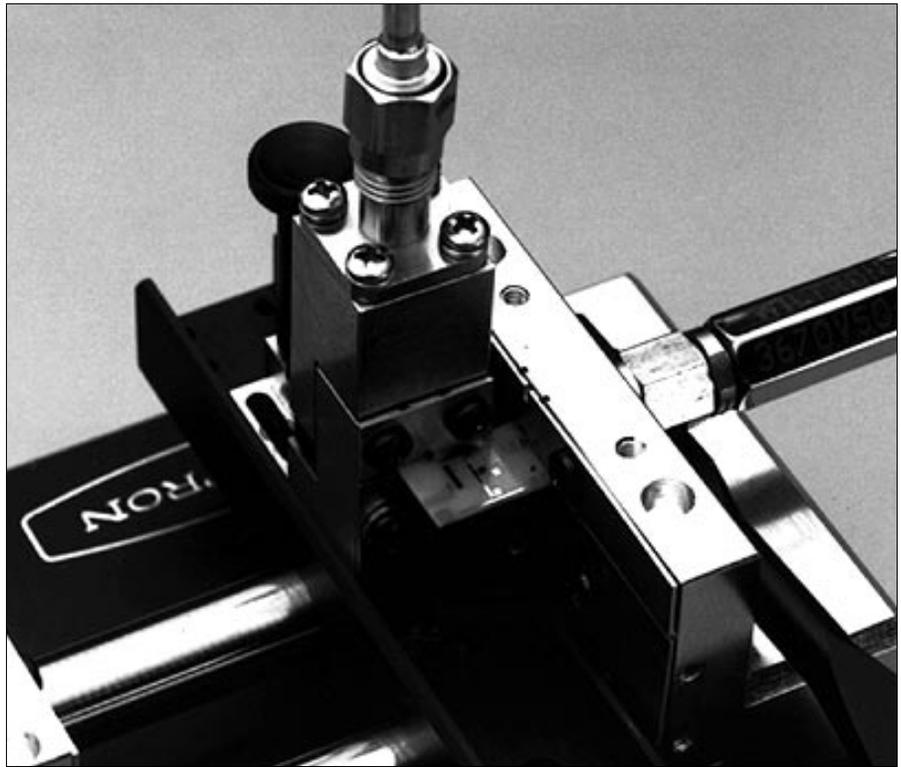
With a 3680-based substrate measurement system, there is not need to force your designs into a straight line or leave your designs untested. The 3680 has the ability to offset lines by as much as $\pm\frac{1}{2}$ inch. Many designs, such as filters, require parallel traces that are offset. In the past, designers were forced to add extra line lengths, create one-of-a-kind custom fixtures, or worse, not test offset designs. With the flexibility of the 3680, you can test offset or in-line designs with one setup. Formerly-untestable designs can now be tested with ease.

Microwave circuit provided by Menlo Industries, Inc.

Right-Angle Measurements

Testing designs with right-angle connections is made easy. The optional right-angle launcher adds a connection at 90° to the fixture. This lets you test devices with right-angle connections with precision and repeatability corresponding to an in-line measurement. The fixture is designed to fit your device; you don't have to design your device to fit the fixture.

The right-angle launcher also provides another benefit – the ability to test multiport devices. With the addition of right-angle launchers, the 3680 can become a three port, or even four port launching fixture. A 360B or 37200A VNA-based microstrip measurement system with optional dual source control can interdependently control up to two sources and a receiver, for testing mixers or other frequency conversion devices. Now a microstrip or CPW mixer, converter, or other device can be tested, with the same convenience as a packaged device.



Microwave circuit provided by Watkins-Johnson Company.



60 GHz Measurements

Wiltron was the first manufacturer to offer a coaxial VNA with continuous 0.04 GHz to 60 GHz measurement capability. With the 3680 Series Universal Test Fixtures, that measurement capability is extended onto the substrate. A Wiltron VNA-based substrate measurement system is capable of measurements from 0.04 GHz to 60 GHz in one setup. And the optional 60 GHz time domain capability provides time or distance measurements with unsurpassed resolution. Discontinuities as close as 1.2 mm on alumina can be resolved. You can measure devices whose performance could previously only be theorized.

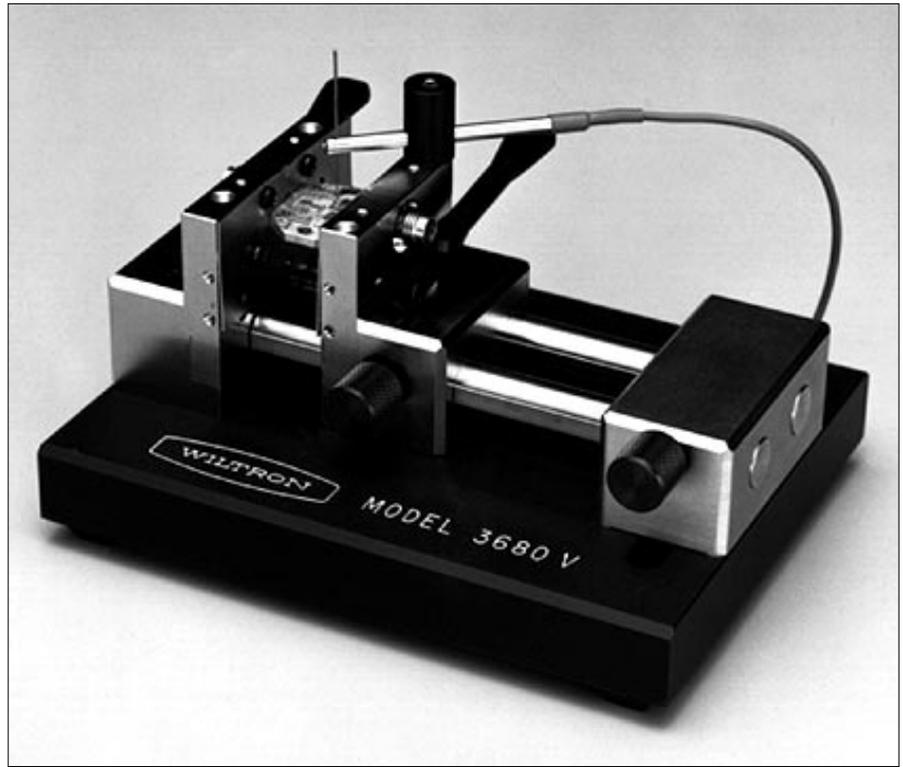
The 3680V, thanks to the patented V Connector, has excellent return loss and insertion loss from DC to 60 GHz. In a substrate measurement system, that translates to improved accuracy and repeatability, for more accurate characterization of your microstrip or CPW designs.

Versatile, For All Your Measurement Needs

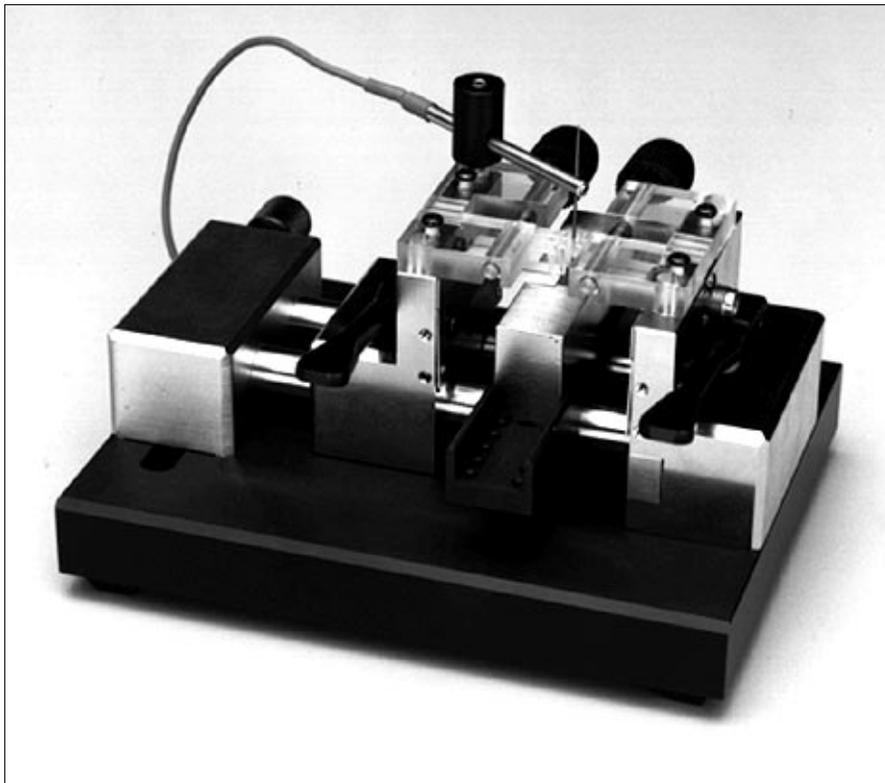
Bias Capability

For active device measurements, the 3680 has bias capability either through the RF connection or through a bias probe. With optional multiple bias probes, you can inject bias into any point on your device under test. The bias probe provides infinite placement resolution and eliminates the need for external bias hardware.

Alternately, if your active device is biased through an RF connection, bias tees can be used to combine bias and RF at any launch point. The 3680's flexible bias injection eliminates the need for multiple fixtures, saving you time and money. Up to four bias probes can be accommodated.



Microwave circuit provided by Fujitsu Microelectronics, Inc.



MMIC Measurements

With the optional MMIC attachment, you can test MMIC's and very small components as conveniently as other devices. A MMIC attachment consists of a center carrier, with microstrip lines for launching, and cam-operated pressure rods. The MMIC component is placed on the center carrier between microstrip lines. (Machinable center carrier blocks are available for your custom designs.) Contact with the component is made with spring tabs, for reliability and damage protection. The unique design of the MMIC attachment assures solid, repeatable measurements on any small device. An Anritsu Wiltron substrate measurement system can fulfill all your substrate measurement needs including, with a MMIC attachment, very small substrates and MMICs.

Calibration/Verification Kits

A full complement of calibration kits for microstrip or coplanar waveguide are available. Standard Open Short Load (OSL) and Line Reflect Line (LRL) calibration components are included. The substrates for these cal kits are carefully selected for proper impedance and consistency, to provide the most accurate measurements possible.

Included with every cal kit is a Beatty standard (standard mismatch) and a 20 dB offset termination. Now you can verify, in the fixture, the quality of your calibrations. This verification, available only from Wiltron, ensures the validity of your device measurements.



Specifications

Mechanical Specifications:

3680 Series Universal Test Fixture

Substrate Types Supported: Microstrip or Coplanar Waveguide

Overall Size: 3680-20: 4.9 W x 7 L x 2.5 H
3680K and 3680V: 4W x 5L x 2.5H in.

Substrate Length: 3680-20: 4.0 in (10 cm) max.
3680K and 3680V: 0.2 in (0.5 cm) minimum
2.0 in. (5 cm) maximum

Substrate Width: No limit on maximum width
0.05 in. (1.2 mm) minimum

Substrate Thickness: 0.005 in. (0.12 mm) minimum
0.075 in. (1.9 mm) maximum

Line Offset: ±0.5 in. (1.2 cm) maximum

Input and Output Connectors:

3680-20: 3.5 mm Female
3680K: K Connector Female
3680V: V Connector Female

36801 K and V Right-Angle Launcher

Distance from In-Line Connector, Axial:

0.4 in. (1 cm) minimum
1.7 in. (4.3 cm) maximum

Distance from In-Line Connector, Offset:

0.0 in. minimum
1.0 in. (2.54 cm) maximum

36802 MMIC Attachment

Substrate Thickness:

Designed for 0.010 in. substrates
(Block can be modified for other thicknesses.)

Test Substrate Length: 0.05 in. (0.12 cm) minimum
0.46 in. (1.17 cm) maximum

Line Offset: ±0.5 in. (1.2 cm) maximum

Electrical Specifications:

Model	Universal Test Fixture			Right-Angle Launcher		MMIC Attachment
	3680-20	3680K	3680V	36801K	36801V	36802
Frequency Range (GHz)	DC to 20	DC to 40	DC to 60	DC to 40	DC to 60	DC to 60
Return Loss (Coax Calibration, dB):						
0.04 to 20 GHz	>17	>17	>17	>16	>16	>15
20 to 40 GHz		>14	>14	>12	>12	> 9
40 to 60 GHz			>10		> 9	> 8
Repeatability of Insertion Loss (dB):						
0.04 to 20 GHz	<±0.10	<±0.10	<±0.10	<±0.15	<±0.15	<±0.20
20 to 40 GHz		<±0.20	<±0.20	<±0.25	<±0.25	<±0.40
40 to 60 GHz			<±0.30		<±0.40	<±0.60

Test Port Characteristics (When used with the Wiltron 360 Vector Network Analyzer)

Test port characteristics apply after optimum 12-term calibration, using a Wiltron 36804 Calibration Kit.

Frequency (GHz)	Directivity (dB)	Source Match (dB)	Load Match (dB)
0.04	>38	>32	>38
1.0	>38	>32	>38
20	>38	>32	>38
30	>34	>26	>34
40	>34	>26	>34
60	>26	>22	>26

*36804-10M (0.04 to 60 GHz); 36804-15M (0.04 to 30 GHz); 36804-25M (0.04 to 20 GHz); and 36804-25C (0.04 to 20 GHz)

Ordering Information

Universal Test Fixtures

3680-20, 20 GHz Universal Test Fixture
3680K, 40 GHz Universal Test Fixture
3680V, 60 GHz Universal Test Fixture

Accessories

36801K, 40 GHz Right-Angle Launcher
36801V, 60 GHz Right-Angle Launcher
36802, MMIC Attachment
36803, Bias Probe

Calibration/Verification Kits

36804 Calibration/Verification Kits
36804-10M, 10 mil Microstrip Cal/Verif. Kit, DC to 60 GHz
36804-15M, 15 mil Microstrip Cal/Verif. Kit, DC to 40 GHz
36804-25M, 25 mil Microstrip Cal/Verif. Kit, DC to 20 GHz
36804-25C, 25 mil CPW Cal/Verif. Kit, DC to 20 GHz
(Includes CPW jaws)
Option 1, adds verification data to any of the above kits

*All trademarks are registered trademarks of their respective companies.
LRL/LRM – Calibration method of Rhode & Schwartz, Germany*

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Central (214) 644-1777
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